Agilent Technologies Advances X-Parameters Innovations

Agilent Technologies announced the latest wave of X-parameter innovations designed to further advance their use and support the industry's rapidly increasing interest in the technology. "X-parameters are a fast-moving technology, and we continue to invest heavily to advance nonlinear measurements and characterization," said Gregg Peters, vice president and general manager of Agilent's Component Test Division. "Within a short period of time, we have built up a solid base of industry-leading customers and partners. This is an exciting area for us and is an example of our long-term belief that there is a unique synergy between our instruments and our Agilent EEsof software products." Agilent's latest X-parameter innovations include the following: -Local fundamental frequency X-parameter measurements simplify the X-parameter simulation of complex, multi-tone systems like super-heterodyne receivers, dramatically reducing file size and memory usage while significantly improving simulation speed by approximately 10 to100 times. -Breakthrough complex system, multi-tone X-parameter simulation performance. In situations where accurate multi-tone simulations are required (e.g., analyzing spurious signals in a complex frequency conversion system), a new adjustable model-reduction algorithm reduces the X-parameter file size and increases simulation performance by approximately 10 to 100 times while maintaining model accuracy. -New Nonlinear Vector Network Analyzer (NVNA) X-parameter capabilities, including three-port mixer/converter, multi-tone and pulsed X-parameters. These capabilities extend the applications for X-parameter measurements by providing richer characterization of a device's nonlinear behavior and capturing bandwidth dependencies. -The powerful combination of the X-parameter model with the simulation and data-display capabilities of Agilent's Advanced Design System software enables engineers to investigate performance in much richer ways than consulting an old-fashioned data sheet with a few graphs, tables and charts. This announcement is timed in concert with the International Microwave Symposium, being held this week in Baltimore, Md. Agilent's X-parameter innovations will be showcased in Booth 813, along with demonstrations of the NVNA, ADS 2011, Genesys and SystemVue solutions. In addition, two MicroApp papers will be presented. Agilent's Dr. Loren Betts will also serve as a panelist at the Microwave Journal Nonlinear Characterization Expert MicroApp Forum. For more information on X-parameters, go to www.agilent.com/find/x-parameters [1]. More information on Agilent's X-parameter industry partnerships is available at www.agilent.com/find/eesof-x-parameters [2]. About Agilent EEsof EDA Software Agilent EEsof EDA is the leading supplier of electronic design automation software for microwave, RF, high-frequency, high-speed digital, RF system, electronic system level, circuit, 3-D electromagnetic, physical design and device-modeling applications. More information is available at www.agilent.com/find/eesof [3]. About Agilent Technologies Agilent Technologies is the world's premier measurement company and a technology leader in chemical analysis, life sciences, electronics and communications. The company's 18,500 employees serve

customers in more than 100 countries. Agilent had net revenues of $5.4 billion in fiscal 2010. Information about Agilent is available at www.agilent.com [4].

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